Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/736,757	CHEN ET AL.
Examiner	Art Unit
Jack I. Berman	2881

	SEARCHED				
Class	Subclass	Date	Examiner		
250	492.21 281 298 492+	2/28/2005	JB		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH N (INCLUDING SEAR	NOTES CH STRATEGY	<b>'</b> )
	DATE	EXMR
EAST search enclosed	2/28/2005	JB
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